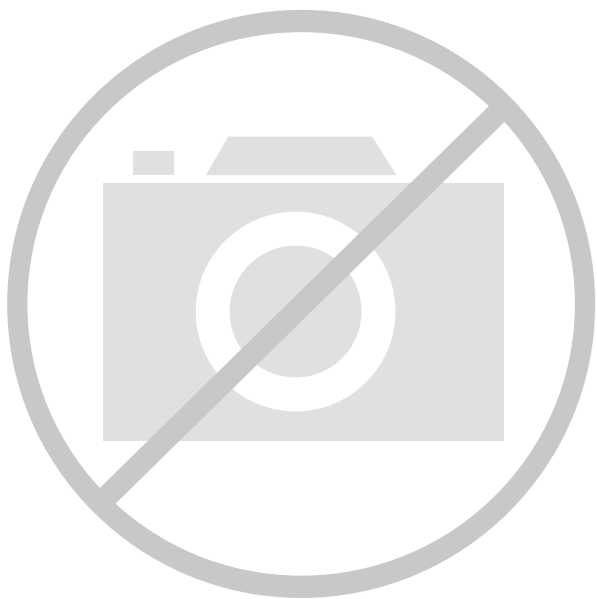




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Embedded - System On Chip (SoC): The Heart of Modern Embedded Systems

Embedded - System On Chip (SoC) refers to an integrated circuit that consolidates all the essential components of a computer system into a single chip. This includes a microprocessor, memory, and other peripherals, all packed into one compact and efficient package. SoCs are designed to provide a complete computing solution, optimizing both space and power consumption, making them ideal for a wide range of embedded applications.

What are Embedded - System On Chip (SoC)?

System On Chip (SoC) integrates multiple functions of a computer or electronic system onto a single chip. Unlike traditional multi-chip solutions, SoCs combine a central

Details

Product Status	Active
Architecture	MCU, FPGA
Core Processor	ARM® Cortex®-M3
Flash Size	512KB
RAM Size	64KB
Peripherals	DMA, POR, WDT
Connectivity	EBI/EMI, Ethernet, I ² C, SPI, UART/USART
Speed	80MHz
Primary Attributes	ProASIC®3 FPGA, 500K Gates, 11520 D-Flip-Flops
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	288-TFBGA, CSPBGA
Supplier Device Package	288-CSP (11x11)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a2f500m3g-csg288

1 – SmartFusion Family Overview

Introduction

The SmartFusion® family of cSoCs builds on the technology first introduced with the Fusion mixed signal FPGAs. SmartFusion cSoCs are made possible by integrating FPGA technology with programmable high-performance analog and hardened ARM Cortex-M3 microcontroller blocks on a flash semiconductor process. The SmartFusion cSoC takes its name from the fact that these three discrete technologies are integrated on a single chip, enabling the lowest cost of ownership and smallest footprint solution to you.

General Description

Microcontroller Subsystem (MSS)

The MSS is composed of a 100 MHz Cortex-M3 processor and integrated peripherals, which are interconnected via a multi-layer AHB bus matrix (ABM). This matrix allows the Cortex-M3 processor, FPGA fabric master, Ethernet media access controller (MAC), when available, and peripheral DMA (PDMA) controller to act as masters to the integrated peripherals, FPGA fabric, embedded nonvolatile memory (eNVM), embedded synchronous RAM (eSRAM), external memory controller (EMC), and analog compute engine (ACE) blocks.

SmartFusion cSoCs of different densities offer various sets of integrated peripherals. Available peripherals include SPI, I²C, and UART serial ports, embedded FlashROM (EFROM), 10/100 Ethernet MAC, timers, phase-locked loops (PLLs), oscillators, real-time counters (RTC), and peripheral DMA controller (PDMA).

Programmable Analog

Analog Front-End (AFE)

SmartFusion cSoCs offer an enhanced analog front-end compared to Fusion devices. The successive approximation register analog-to-digital converters (SAR ADC) are similar to those found on Fusion devices. SmartFusion cSoC also adds first order sigma-delta digital-to-analog converters (SDD DAC).

SmartFusion cSoCs can handle multiple analog signals simultaneously with its signal conditioning blocks (SCBs). SCBs are made of a combination of active bipolar prescalers (ABPS), comparators, current monitors and temperature monitors. ABPS modules allow larger bipolar voltages to be fed to the ADC. Current monitors take the voltage across an external sense resistor and convert it to a voltage suitable for the ADC input range. Similarly, the temperature monitor reads the current through an external PN-junction (diode or transistor) and converts it internally for the ADC. The SCB also includes comparators to monitor fast signal thresholds without using the ADC. The output of the comparators can be fed to the analog compute engine or the ADC.

Analog Compute Engine (ACE)

The mixed signal blocks found in SmartFusion cSoCs are controlled and connected to the rest of the system via a dedicated processor called the analog compute engine (ACE). The role of the ACE is to offload control of the analog blocks from the Cortex-M3, thus offering faster throughput or better power consumption compared to a system where the main processor is in charge of monitoring the analog resources. The ACE is built to handle sampling, sequencing, and post-processing of the ADCs, DACs, and SCBs.

ProASIC3 FPGA Fabric

The SmartFusion cSoC family, based on the proven, low power, firm-error immune ProASIC®3 flash FPGA architecture, benefits from the advantages only flash-based devices offer:

Reduced Cost of Ownership

Advantages to the designer extend beyond low unit cost, high performance, and ease of use. Flash-based SmartFusion cSoCs are Instant On and do not need to be loaded from an external boot PROM at each power-up. On-board security mechanisms prevent access to the programming information and enable secure remote updates of the FPGA logic. Designers can perform secure remote in-system programming (ISP) to support future design iterations and critical field upgrades, with confidence that valuable IP cannot be compromised or copied. Secure ISP can be performed using the industry standard AES algorithm with MAC data authentication on the device.

Low Power

Flash-based SmartFusion cSoCs exhibit power characteristics similar to those of an ASIC, making them an ideal choice for power-sensitive applications. With SmartFusion cSoCs, there is no power-on current and no high current transition, both of which are common with SRAM-based FPGAs.

SmartFusion cSoCs also have low dynamic power consumption and support very low power time-keeping mode, offering further power savings.

Security

As the nonvolatile, flash-based SmartFusion cSoC family requires no boot PROM, there is no vulnerable external bitstream. SmartFusion cSoCs incorporate FlashLock®, which provides a unique combination of reprogrammability and design security without external overhead, advantages that only a device with nonvolatile flash programming can offer.

SmartFusion cSoCs utilize a 128-bit flash-based key lock and a separate AES key to provide security for programmed IP and configuration data. The FlashROM data in Fusion devices can also be encrypted prior to loading. Additionally, the flash memory blocks can be programmed during runtime using the AES-128 block cipher encryption standard (FIPS Publication 192).

SmartFusion cSoCs with AES-based security are designed to provide protection for remote field updates over public networks, such as the Internet, and help to ensure that valuable IP remains out of the hands of system overbuilders, system cloners, and IP thieves. As an additional security measure, the FPGA configuration data of a programmed Fusion device cannot be read back, although secure design verification is possible. During design, the user controls and defines both internal and external access to the flash memory blocks.

Security, built into the FPGA fabric, is an inherent component of the SmartFusion cSoC family. The flash cells are located beneath seven metal layers, and many device design and layout techniques have been used to make invasive attacks extremely difficult. SmartFusion cSoCs, with FlashLock and AES security, are unique in being highly resistant to both invasive and noninvasive attacks. Your valuable IP is protected with industry standard security measures, making remote ISP feasible. A SmartFusion cSoC provides the highest security available for programmable logic designs.

Single Chip

Flash-based FPGAs store their configuration information in on-chip flash cells. Once programmed, the configuration data is an inherent part of the FPGA structure, and no external configuration data needs to be loaded at system power-up (unlike SRAM-based FPGAs). Therefore, flash-based SmartFusion cSoCs do not require system configuration components such as electrically erasable programmable read-only memories (EEPROMs) or microcontrollers to load device configuration data during power-up. This reduces bill-of-materials costs and PCB area, and increases system security and reliability.

Instant On

Flash-based SmartFusion cSoCs are Instant On. Instant On SmartFusion cSoCs greatly simplify total system design and reduce total system cost by eliminating the need for complex programmable logic devices (CPLDs). SmartFusion Instant On clocking (PLLs) replace off-chip clocking resources. In addition, glitches and brownouts in system power will not corrupt the SmartFusion flash configuration. Unlike SRAM-based FPGAs, the device will not have to be reloaded when system power is restored.

2 – SmartFusion DC and Switching Characteristics

General Specifications

Operating Conditions

Stresses beyond the operating conditions listed in [Table 2-1](#) may cause permanent damage to the device.

Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Absolute Maximum Ratings are stress ratings only; functional operation of the device at these or any other conditions beyond those listed under the Recommended Operating Conditions specified in [Table 2-3 on page 2-3](#) is not implied.

Table 2-1 • Absolute Maximum Ratings

Symbol	Parameter	Limits	Units
VCC	DC core supply voltage	–0.3 to 1.65	V
VJTAG	JTAG DC voltage	–0.3 to 3.75	V
VPP	Programming voltage	–0.3 to 3.75	V
VCCPLLx	Analog power supply (PLL)	–0.3 to 1.65	V
VCCFPGAIOBx	DC FPGA I/O buffer supply voltage	–0.3 to 3.75	V
VCCMSSIOBx	DC MSS I/O buffer supply voltage	–0.3 to 3.75	V
VI	I/O input voltage	–0.3 V to 3.6 V (when I/O hot insertion mode is enabled) –0.3 V to (VCCxxxIOBx + 1 V) or 3.6 V, whichever voltage is lower (when I/O hot-insertion mode is disabled)	V
VCC33A	Analog clean 3.3 V supply to the analog circuitry	–0.3 to 3.75	V
VCC33ADCx	Analog 3.3 V supply to ADC	–0.3 to 3.75	V
VCC33AP	Analog clean 3.3 V supply to the charge pump	–0.3 to 3.75	V
VCC33SDDx	Analog 3.3 V supply to the sigma-delta DAC	–0.3 to 3.75	V
VAREFx	Voltage reference for ADC	1.0 to 3.75	V
VCCRCOSC	Analog supply to the integrated RC oscillator	–0.3 to 3.75	V
VDDBAT	External battery supply	–0.3 to 3.75	V
VCCMAINXTAL	Analog supply to the main crystal oscillator	–0.3 to 3.75	V
VCCLPXTAL	Analog supply to the low power 32 kHz crystal oscillator	–0.3 to 3.75	V
VCCENVM	Embedded nonvolatile memory supply	–0.3 to 1.65	V
VCCESRAM	Embedded SRAM supply	–0.3 to 1.65	V
VCC15A	Analog 1.5 V supply to the analog circuitry	–0.3 to 1.65	V
VCC15ADCx	Analog 1.5 V supply to the ADC	–0.3 to 1.65	V
T _{STG} ¹	Storage temperature	–65 to +150	°C
T _J ¹	Junction temperature	125	°C

Notes:

1. For flash programming and retention maximum limits, refer to [Table 2-4 on page 2-4](#). For recommended operating conditions, refer to [Table 2-3 on page 2-3](#).
2. The device should be operated within the limits specified by the datasheet. During transitions, the input signal may undershoot or overshoot according to the limits shown in [Table 2-5 on page 2-4](#).

Table 2-28 • I/O Output Buffer Maximum Resistances¹
Applicable to MSS I/O Banks

Standard	Drive Strength	R _{PULL-DOWN} (Ω) ²	R _{PULL-UP} (Ω) ³
3.3 V LVTTTL / 3.3 V LVCMOS	8mA	50	150
2.5 V LVCMOS	8 mA	50	100
1.8 V LVCMOS	4 mA	100	112
1.5 V LVCMOS	2 mA	200	224

Notes:

1. These maximum values are provided for informational reasons only. Minimum output buffer resistance values depend on VCCxxxIOBx, drive strength selection, temperature, and process. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the [Microsemi SoC Products Group website](#).
2. $R_{(PULL-DOWN-MAX)} = (V_{OLspec}) / I_{OLspec}$
3. $R_{(PULL-UP-MAX)} = (V_{CCI\max} - V_{OHspec}) / I_{OHspec}$

Table 2-29 • I/O Weak Pull-Up/Pull-Down Resistances
Minimum and Maximum Weak Pull-Up/Pull-Down Resistance Values

VCCxxxIOBx	R _(WEAK PULL-UP) ¹ (Ω)		R _(WEAK PULL-DOWN) ² (Ω)	
	Min.	Max.	Min.	Max.
3.3 V	10 k	45 k	10 k	45 k
2.5 V	11 k	55 k	12 k	74 k
1.8 V	18 k	70 k	17 k	110 k
1.5 V	19 k	90 k	19 k	140 k

Notes:

1. $R_{(WEAK PULL-UP-MAX)} = (V_{CCI\max} - V_{OHspec}) / I_{(WEAK PULL-UP-MIN)}$
2. $R_{(WEAK PULL-DOWN-MAX)} = (V_{OLspec}) / I_{(WEAK PULL-DOWN-MIN)}$

Table 2-52 • 1.8 V LVCMOS High Slew
Worst Commercial-Case Conditions: $T_J = 85^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$,
Worst-Case $V_{CC} \times \text{IOBx} = 1.7\text{ V}$
Applicable to MSS I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{PYS}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	Units
4 mA	Std.	0.22	2.77	0.09	1.09	1.64	0.22	2.82	2.72	2.21	2.25	ns
	–1	0.18	2.31	0.07	0.91	1.37	0.18	2.35	2.27	1.84	1.87	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-9](#) for derating values.

DDR Module Specifications

Input DDR Module

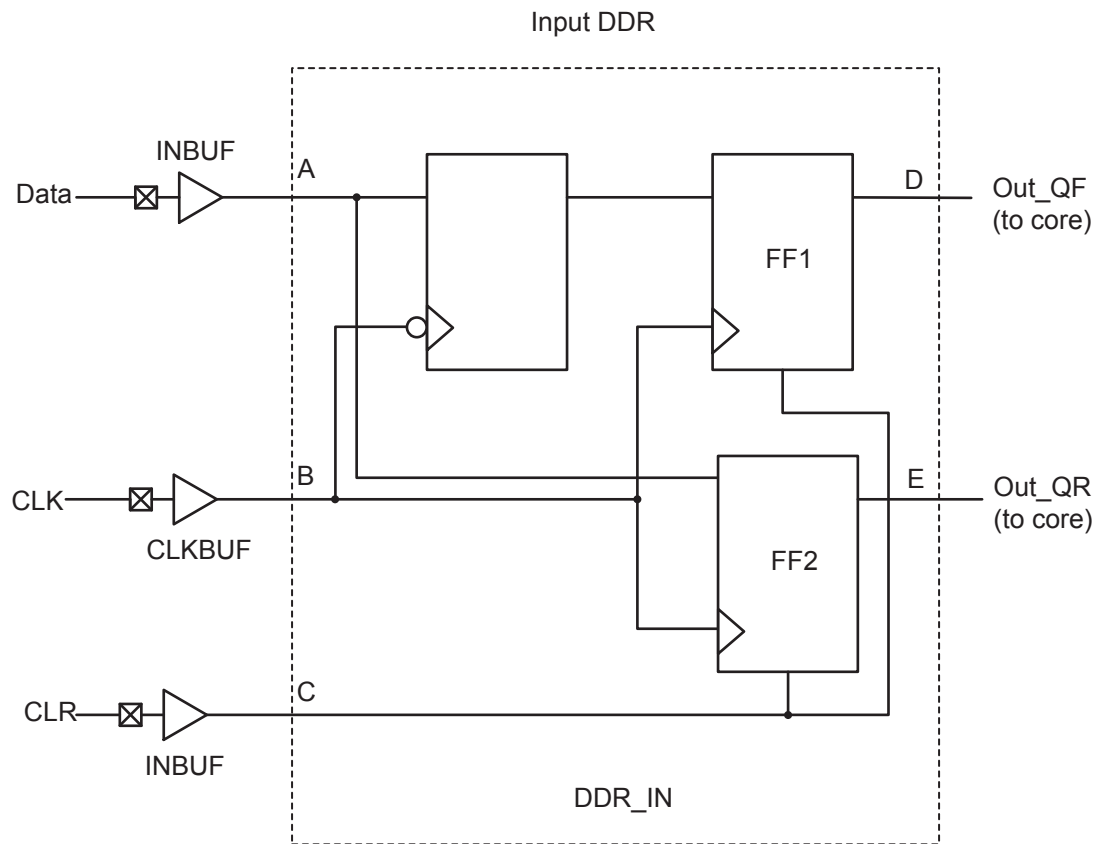


Figure 2-19 • Input DDR Timing Model

Table 2-74 • Parameter Definitions

Parameter Name	Parameter Definition	Measuring Nodes (from, to)
$t_{DDRICKQ1}$	Clock-to-Out Out_QR	B, D
$t_{DDRICKQ2}$	Clock-to-Out Out_QF	B, E
$t_{DDRISUD}$	Data Setup Time of DDR input	A, B
t_{DDRIHD}	Data Hold Time of DDR input	A, B
$t_{DDRICLR2Q1}$	Clear-to-Out Out_QR	C, D
$t_{DDRICLR2Q2}$	Clear-to-Out Out_QF	C, E
$t_{DDRIREMCLR}$	Clear Removal	C, B
$t_{DDRIRECCLR}$	Clear Recovery	C, B

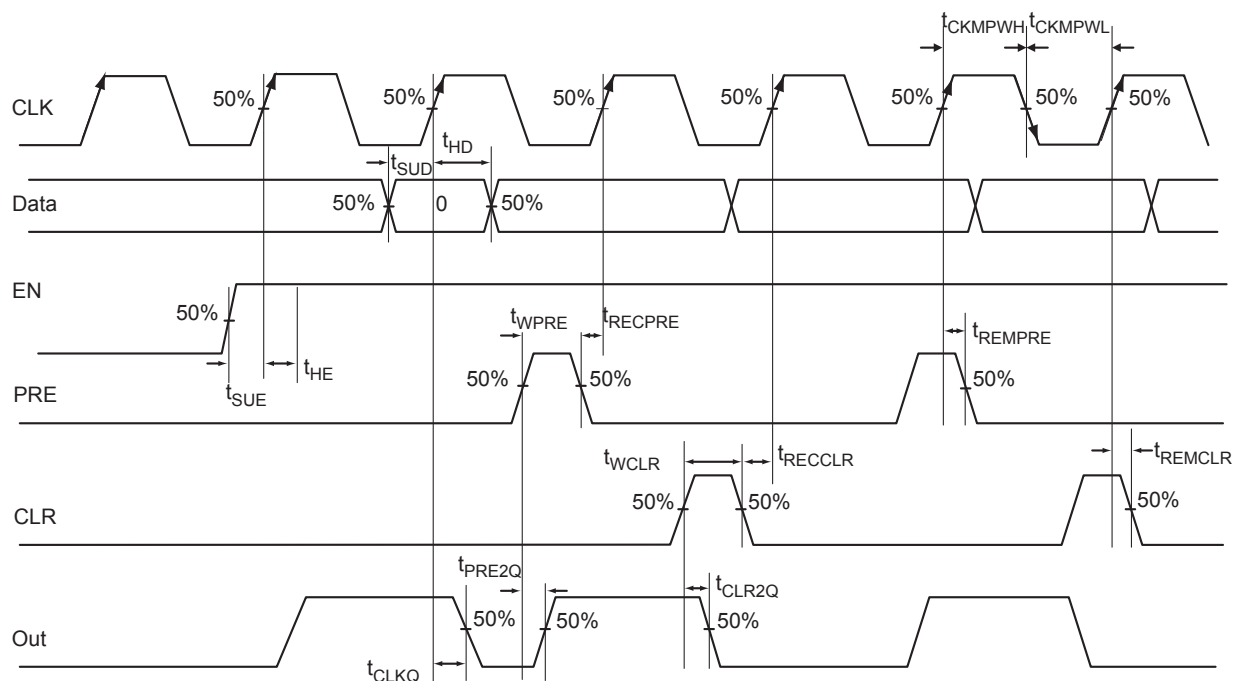


Figure 2-26 • Timing Model and Waveforms

Timing Characteristics

Table 2-79 • Register Delays

Worst Commercial-Case Conditions: $T_J = 85^\circ\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$

Parameter	Description	-1	Std.	Units
t_{CLKQ}	Clock-to-Q of the Core Register	0.56	0.67	ns
t_{SUD}	Data Setup Time for the Core Register	0.44	0.52	ns
t_{HD}	Data Hold Time for the Core Register	0.00	0.00	ns
t_{SUE}	Enable Setup Time for the Core Register	0.46	0.55	ns
t_{HE}	Enable Hold Time for the Core Register	0.00	0.00	ns
t_{CLR2Q}	Asynchronous Clear-to-Q of the Core Register	0.41	0.49	ns
t_{PRE2Q}	Asynchronous Preset-to-Q of the Core Register	0.41	0.49	ns
t_{REMCLR}	Asynchronous Clear Removal Time for the Core Register	0.00	0.00	ns
t_{RECCLR}	Asynchronous Clear Recovery Time for the Core Register	0.23	0.27	ns
t_{REMPRE}	Asynchronous Preset Removal Time for the Core Register	0.00	0.00	ns
t_{RECPRE}	Asynchronous Preset Recovery Time for the Core Register	0.23	0.27	ns
t_{WCLR}	Asynchronous Clear Minimum Pulse Width for the Core Register	0.22	0.22	ns
t_{WPRE}	Asynchronous Preset Minimum Pulse Width for the Core Register	0.22	0.22	ns
t_{CKMPWH}	Clock Minimum Pulse Width High for the Core Register	0.32	0.32	ns
t_{CKMPWL}	Clock Minimum Pulse Width Low for the Core Register	0.36	0.36	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-9](#) for derating values.

Table 2-82 • A2F060 Global Resource
Worst Commercial-Case Conditions: $T_J = 85^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$

Parameter	Description	–1		Std.		Units
		Min. ¹	Max. ²	Min. ¹	Max. ²	
t_{RCKL}	Input Low Delay for Global Clock	0.75	0.96	0.90	1.15	ns
t_{RCKH}	Input High Delay for Global Clock	0.72	0.98	0.86	1.17	ns
t_{RCKMPWH}	Minimum Pulse Width High for Global Clock	0.85		1.00		ns
t_{RCKMPWL}	Minimum Pulse Width Low for Global Clock	0.85		1.00		ns
t_{RCKSW}	Maximum Skew for Global Clock		0.26		0.31	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage-supply levels, refer to [Table 2-7 on page 2-9](#) for derating values.

RC Oscillator

The table below describes the electrical characteristics of the RC oscillator.

RC Oscillator Characteristics

Table 2-83 • Electrical Characteristics of the RC Oscillator

Parameter	Description	Condition	Min.	Typ.	Max.	Units
FRC	Operating frequency			100		MHz
	Accuracy	Temperature: -40°C to 100°C Voltage: $3.3\text{ V} \pm 5\%$		1		%
	Output jitter	Period jitter (at 5 K cycles)		100		ps RMS
		Cycle-to-cycle jitter (at 5 K cycles)		100		ps RMS
		Period jitter (at 5 K cycles) with 1 KHz / 300 mV peak-to-peak noise on power supply		150		ps RMS
		Cycle-to-cycle jitter (at 5 K cycles) with 1 KHz / 300 mV peak-to-peak noise on power supply		150		ps RMS
	Output duty cycle			50		%
IDYNRC	Operating current	3.3 V domain		1		mA
		1.5 V domain		2		mA

Table 2-96 • ABPS Performance Specifications (continued)

Specification	Test Conditions	Min.	Typ.	Max.	Units
Input referred offset voltage					
	GDEC[1:0] = 11	−0.31	−0.07	0.31	% FS*
	−40°C to +100°C	−1.00		1.47	% FS*
	GDEC[1:0] = 10	−0.34	−0.07	0.34	% FS*
	−40°C to +100°C	−0.90		1.37	% FS*
	GDEC[1:0] = 01	−0.61	−0.07	0.35	% FS*
	−40°C to +100°C	−1.05		1.35	% FS*
	GDEC[1:0] = 00	−0.39	−0.07	0.35	% FS*
	−40°C to +100°C	−1.06		1.38	% FS*
SINAD		53	56		dB
Non-linearity	RMS deviation from BFLS			0.5	% FS*
Effective number of bits (ENOB) $\text{ENOB} = \frac{\text{SINAD} - 1.76 \text{ dB}}{6.02 \text{ dB/bit}}$ EQ 11	GDEC[1:0] = 11 (±2.56 range), −1 dBFS input				
	12-bit mode 10 KHz	8.6	9.1		Bits
	12-bit mode 100 KHz	8.6	9.1		Bits
	10-bit mode 10 KHz	8.5	8.9		Bits
	10-bit mode 100 KHz	8.5	8.9		Bits
	8-bit mode 10 KHz	7.7	7.8		Bits
	8-bit mode 100 KHz	7.7	7.8		Bits
Large-signal bandwidth	−1 dBFS input		1		MHz
Analog settling time	To 0.1% of final value (with ADC load)			10	μs
Input resistance			1		MΩ
Power supply rejection ratio	DC (0–1 KHz)	38	40		dB
ABPS power supply current requirements (not including ADC or VAREF _x)	ABPS_EN = 1 (operational mode)				
	VCC33A		123	134	μA
	VCC33AP		89	94	μA
	VCC15A		1		μA

Note: *FS is full-scale error, defined as the difference between the actual value that triggers the transition to full-scale and the ideal analog full-scale transition value. Full-scale error equals offset error plus gain error. Refer to the Analog-to-Digital Converter chapter of the [SmartFusion Programmable Analog User's Guide](#) for more information.

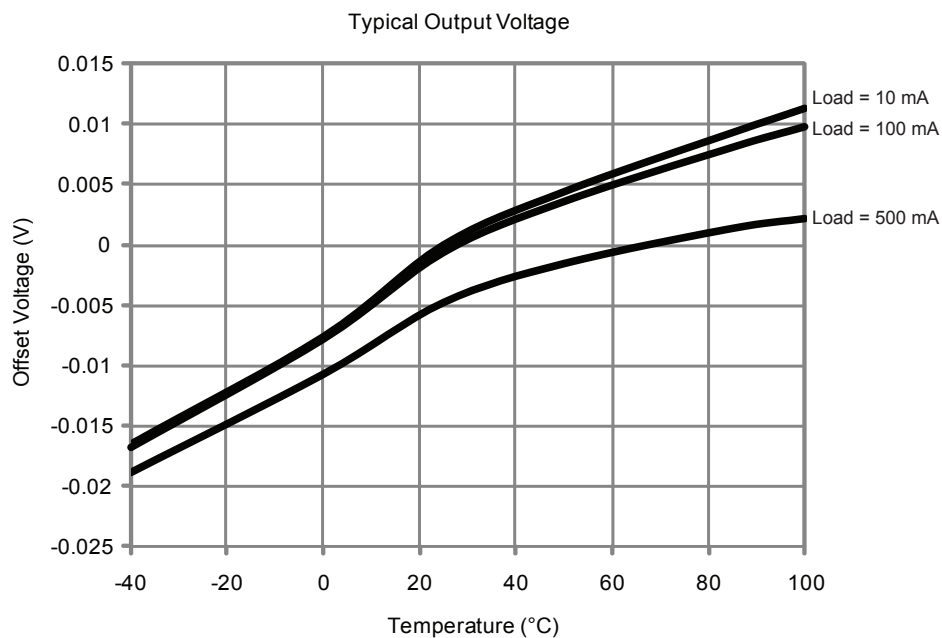


Figure 2-45 • Typical Output Voltage

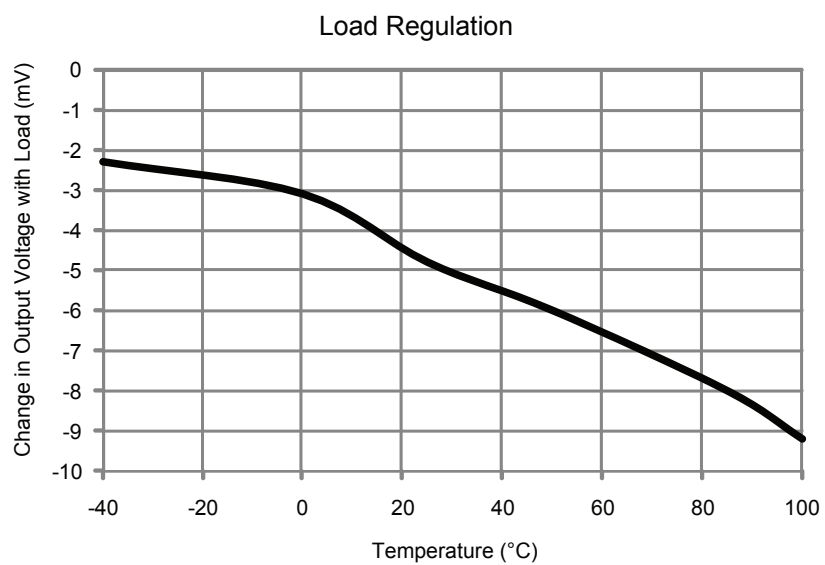


Figure 2-46 • Load Regulation

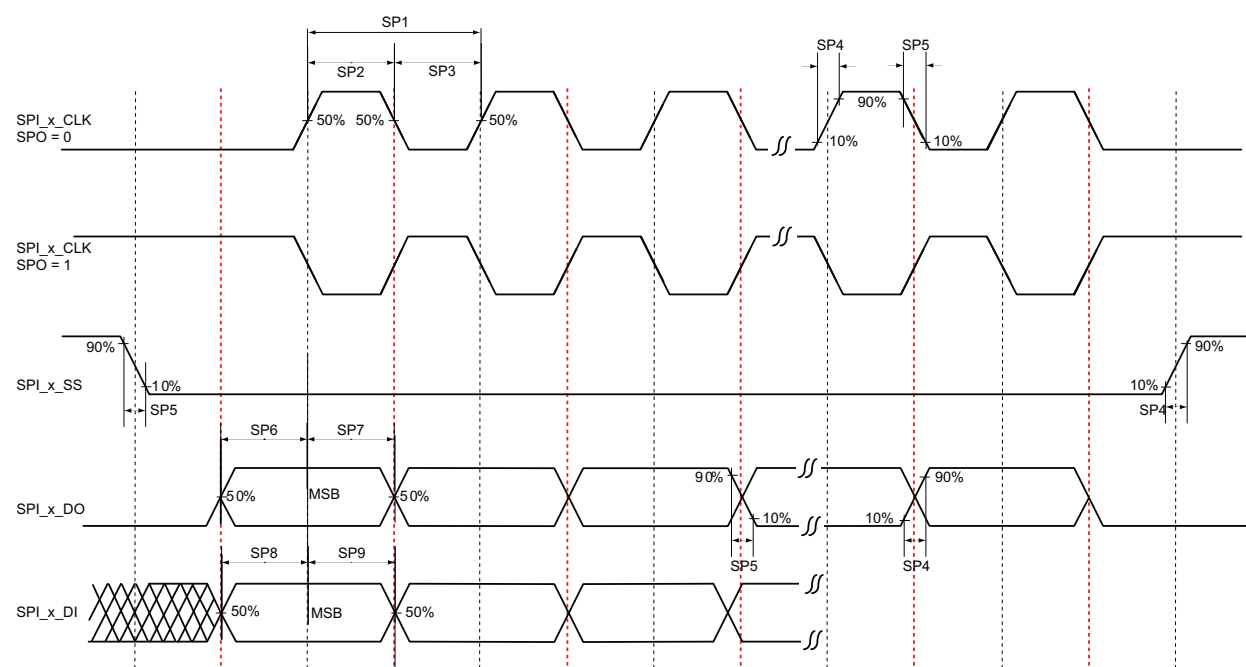
Table 2-100 • SPI Characteristics

Commercial Case Conditions: $T_J = 85^\circ\text{C}$, $V_{DD} = 1.425\text{ V}$, -1 Speed Grade (continued)

Symbol	Description and Condition	A2F060	A2F200	A2F500	Unit
sp6	Data from master (SPI_x_DO) setup time ²	1	1	1	clk cycles
sp7	Data from master (SPI_x_DO) hold time ²	1	1	1	clk cycles
sp8	SPI_x_DI setup time ²	1	1	1	clk cycles
sp9	SPI_x_DI hold time ²	1	1	1	clk cycles

Notes:

- These values are provided for a load of 35 pF. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the Microsemi SoC Products Group website:
http://www.microsemi.com/index.php?option=com_microsemi&Itemid=489&lang=en&view=salescontact
- For allowable clk configurations, refer to the Serial Peripheral Interface Controller section in the *SmartFusion Microcontroller Subsystem User's Guide*.


Figure 2-47 • SPI Timing for a Single Frame Transfer in Motorola Mode (SPH = 1)

Inter-Integrated Circuit (I²C) Characteristics

This section describes the DC and switching of the I²C interface. Unless otherwise noted, all output characteristics given are for a 100 pF load on the pins. For timing parameter definitions, refer to [Figure 2-48 on page 2-92](#).

Table 2-101 • I²C Characteristics

Commercial Case Conditions: T_J = 85°C, V_{DD} = 1.425 V, –1 Speed Grade

Parameter	Definition	Condition	Value	Unit
V _{IL}	Minimum input low voltage	–	See Table 2-36 on page 2-30	–
	Maximum input low voltage	–	See Table 2-36	–
V _{IH}	Minimum input high voltage	–	See Table 2-36	–
	Maximum input high voltage	–	See Table 2-36	–
V _{OL}	Maximum output voltage low	I _{OL} = 8 mA	See Table 2-36	–
I _{IL}	Input current high	–	See Table 2-36	–
I _{IH}	Input current low	–	See Table 2-36	–
V _{hyst}	Hysteresis of Schmitt trigger inputs	–	See Table 2-33 on page 2-29	V
T _{FALL}	Fall time ²	VIHmin to VILMax, C _{load} = 400 pF	15.0	ns
		VIHmin to VILMax, C _{load} = 100 pF	4.0	ns
T _{RISE}	Rise time ²	VILMax to VIHmin, C _{load} = 400pF	19.5	ns
		VILMax to VIHmin, C _{load} = 100pF	5.2	ns
C _{in}	Pin capacitance	V _{IN} = 0, f = 1.0 MHz	8.0	pF
R _{pull-up}	Output buffer maximum pull-down Resistance ¹	–	50	Ω
R _{pull-down}	Output buffer maximum pull-up Resistance ¹	–	150	Ω
D _{max}	Maximum data rate	Fast mode	400	Kbps
t _{LOW}	Low period of I2C_x_SCL ³	–	1	clk cycles
t _{HIGH}	High period of I2C_x_SCL ³	–	1	clk cycles
t _{HD;STA}	START hold time ³	–	1	clk cycles
t _{SU;STA}	START setup time ³	–	1	clk cycles
t _{HD;DAT}	DATA hold time ³	–	1	clk cycles
t _{SU;DAT}	DATA setup time ³	–	1	clk cycles

Notes:

1. These maximum values are provided for information only. Minimum output buffer resistance values depend on VCCxxxIOBx, drive strength selection, temperature, and process. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the SoC Products Group website at http://www.microsemi.com/index.php?option=com_microsemi&Itemid=489&lang=en&view=salescontact.
2. These values are provided for a load of 100 pF and 400 pF. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located on the SoC Products Group website at http://www.microsemi.com/index.php?option=com_microsemi&Itemid=489&lang=en&view=salescontact.
3. For allowable Pclk configurations, refer to the Inter-Integrated Circuit (I²C) Peripherals section in the [SmartFusion Microcontroller Subsystem User's Guide](#).

User I/O Naming Conventions

The naming convention used for each FPGA user I/O is Gmn/IOuxwByVz, where:

Gmn is only used for I/Os that also have CCC access—i.e., global pins. Refer to the ["Global I/O Naming Conventions" section on page 5-6](#).

u = I/O pair number in bank, starting at 00 from the northwest I/O bank and proceeding in a clockwise direction.

x = P (positive) or N (negative) or S (single-ended) or R (regular, single-ended).

w = D (Differential Pair), P (Pair), or S (Single-Ended). D (Differential Pair) if both members of the pair are bonded out to adjacent pins or are separated only by one GND or NC pin; P (Pair) if both members of the pair are bonded out but do not meet the adjacency requirement; or S (Single-Ended) if the I/O pair is not bonded out. For Differential Pairs (D), adjacency for ball grid packages means only vertical or horizontal. Diagonal adjacency does not meet the requirements for a true differential pair.

B = Bank

y = Bank number starting at 0 from northwest I/O bank and incrementing clockwise.

V = Reference voltage

z = VREF mini bank number.

The FPGA user I/O pin functions as an input, output, tristate or bidirectional buffer. Input and output signal levels are compatible with the I/O standard selected. Unused I/O pins are disabled by Libero SoC software and include a weak pull-up resistor. During power-up, the used I/O pins are tristated with no pull-up or pull-down resistors until I/O enable (there is a delay after voltage stabilizes, and different I/O banks power up sequentially to avoid a surge of ICCI).

Unused I/Os are configured as follows:

- Output buffer is disabled (with tristate value of high impedance)
- Input buffer is disabled (with tristate value of high impedance)
- Weak pull-up is programmed

Some of these pins are also multiplexed with integrated peripherals in the MSS (Ethernet MAC and external memory controller).

All unused MSS I/Os are tristated by default (with output buffer disabled). However, you can configure it as weak pull-up or pull-down by using Libero SoC I/O attributor window. The Schmitt trigger is disabled. Essentially, I/Os have the reset values as defined in Table 19-25 IOMUX_n_CR, in the [SmartFusion Microcontroller Subsystem User's Guide](#).

By default, during programming I/Os become tristated and weakly pulled up to VCCxxxIOBx. You can modify the I/O states during programming in FlashPro. For more details, refer to ["Specifying I/O States During Programming" on page 1-3](#). With the VCCI and VCC supplies continuously powered up, when the device transitions from programming to operating mode, the I/Os are instantly configured to the desired user configuration. For more information, see the SmartFusion FPGA User I/Os section in the [SmartFusion FPGA Fabric User's Guide](#).

Special Function Pins

Name	Type	Polarity/Bus Size	Description
NC			No connect This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.
DC			Do not connect. This pin should not be connected to any signals on the PCB. These pins should be left unconnected.
LPXIN	In	1	Low power 32 KHz crystal oscillator. Input from the 32 KHz oscillator. Pin for connecting a low power 32 KHz watch crystal. If not used, the LPXIN pin can be left floating. For more information, see the PLLs, Clock Conditioning Circuitry, and On-Chip Crystal Oscillators section in the SmartFusion Microcontroller Subsystem User's Guide .
LPXOUT	In	1	Low power 32 KHz crystal oscillator. Output to the 32 KHz oscillator. Pin for connecting a low power 32 KHz watch crystal. If not used, the LPXOUT pin can be left floating. For more information, see the PLLs, Clock Conditioning Circuitry, and On-Chip Crystal Oscillators section in the SmartFusion Microcontroller Subsystem User's Guide .
MAINXIN	In	1	Main crystal oscillator circuit. Input to the crystal oscillator circuit. Pin for connecting an external crystal, ceramic resonator, or RC network. When using an external crystal or ceramic oscillator, external capacitors are also recommended. Refer to documentation from the crystal oscillator manufacturer for proper capacitor value. If an external RC network or clock input is used, the RC components are connected to the MAINXIN pin, with MAINXOUT left floating. When the main crystal oscillator is not being used, MAINXIN and MAINXOUT pins can be left floating. For more information, see the PLLs, Clock Conditioning Circuitry, and On-Chip Crystal Oscillators section in the SmartFusion Microcontroller Subsystem User's Guide .
MAINXOUT	Out	1	Main crystal oscillator circuit. Output from the crystal oscillator circuit. Pin for connecting external crystal or ceramic resonator. When using an external crystal or ceramic oscillator, external capacitors are also recommended. Refer to documentation from the crystal oscillator manufacturer for proper capacitor value. If an external RC network or clock input is used, the RC components are connected to the MAINXIN pin, with MAINXOUT left floating. When the main crystal oscillator is not being used, MAINXIN and MAINXOUT pins can be left floating. For more information, see the PLLs, Clock Conditioning Circuitry, and On-Chip Crystal Oscillators section in the SmartFusion Microcontroller Subsystem User's Guide .

Pin Number	PQ208	
	A2F200	A2F500
32	VCCRCOSC	VCCRCOSC
33	MSS_RESET_N	MSS_RESET_N
34	VCCESRAM	VCCESRAM
35	MAC_MDC/IO48RSB4V0	MAC_MDC/IO57RSB4V0
36	MAC_MDIO/IO49RSB4V0	MAC_MDIO/IO58RSB4V0
37	MAC_TXEN/IO52RSB4V0	MAC_TXEN/IO61RSB4V0
38	MAC_CRSDV/IO51RSB4V0	MAC_CRSDV/IO60RSB4V0
39	MAC_RXER/IO50RSB4V0	MAC_RXER/IO59RSB4V0
40	GND	GND
41	VCCMSSIOB4	VCCMSSIOB4
42	VCC	VCC
43	MAC_TXD[0]/IO56RSB4V0	MAC_TXD[0]/IO65RSB4V0
44	MAC_TXD[1]/IO55RSB4V0	MAC_TXD[1]/IO64RSB4V0
45	MAC_RXD[0]/IO54RSB4V0	MAC_RXD[0]/IO63RSB4V0
46	MAC_RXD[1]/IO53RSB4V0	MAC_RXD[1]/IO62RSB4V0
47	MAC_CLK	MAC_CLK
48	GNDSDD0	GNDSDD0
49	VCC33SDD0	VCC33SDD0
50	VCC15A	VCC15A
51	PCAP	PCAP
52	NCAP	NCAP
53	VCC33AP	VCC33AP
54	VCC33N	VCC33N
55	SDD0	SDD0
56	GNDA	GNDA
57	GNDAQ	GNDAQ
58	ABPS0	ABPS0
59	ABPS1	ABPS1
60	CM0	CM0
61	TM0	TM0
62	GNDTM0	GNDTM0

Notes:

1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.

Pin Number	PQ208	
	A2F200	A2F500
63	TM1	TM1
64	CM1	CM1
65	ABPS3	ABPS3
66	ABPS2	ABPS2
67	ADC0	ADC0
68	ADC1	ADC1
69	ADC2	ADC2
70	ADC3	ADC3
71	VAREF0	VAREF0
72	GND33ADC0	GND33ADC0
73	VCC33ADC0	VCC33ADC0
74	GND33ADC0	GND33ADC0
75	VCC15ADC0	VCC15ADC0
76	GND15ADC0	GND15ADC0
77	GND15ADC1	GND15ADC1
78	VCC15ADC1	VCC15ADC1
79	GND33ADC1	GND33ADC1
80	VCC33ADC1	VCC33ADC1
81	GND33ADC1	GND33ADC1
82	VAREF1	VAREF1
83	ADC7	ADC7
84	ADC6	ADC6
85	ADC5	ADC5
86	ADC4	ADC4
87	ABPS6	ABPS6
88	ABPS7	ABPS7
89	CM3	CM3
90	TM3	TM3
91	GNDTM1	GNDTM1
92	TM2	TM2
93	CM2	CM2

Notes:

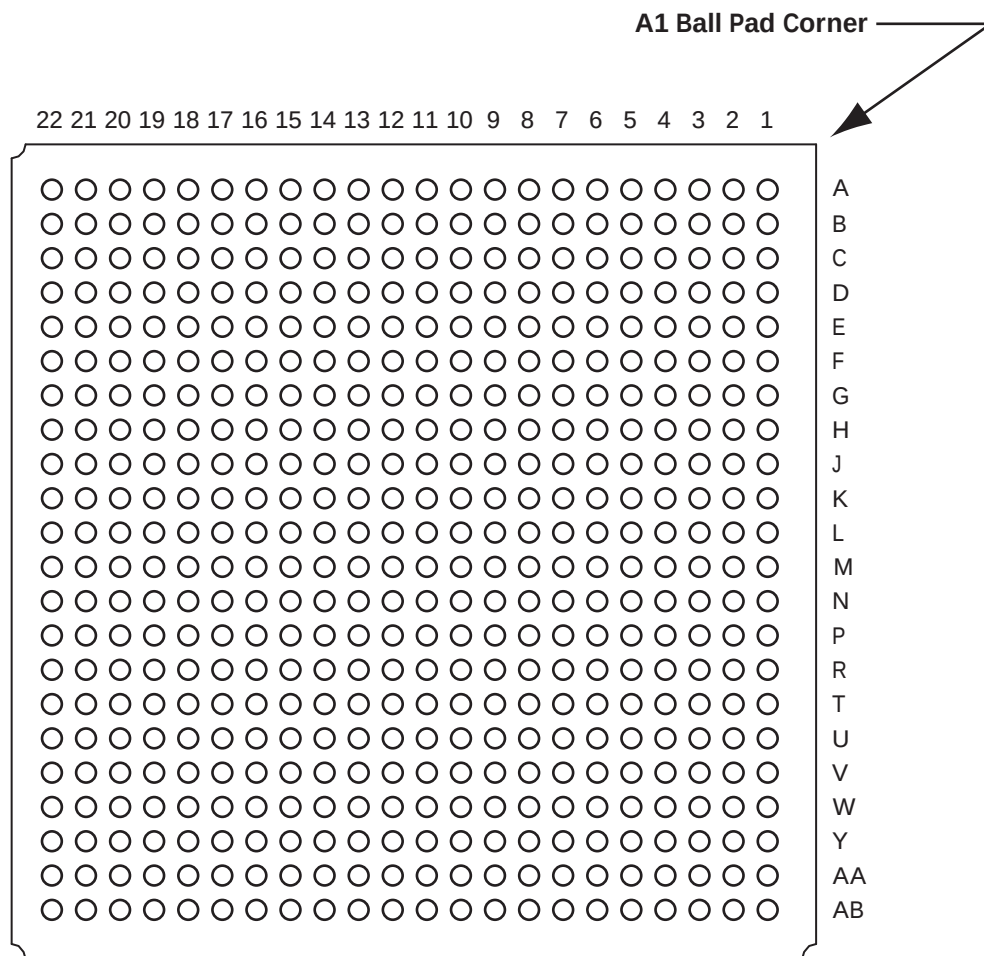
1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.

Pin No.	FG256		
	A2F060 Function	A2F200 Function	A2F500 Function
F14	IO21NDB1V0	GCB0/IO27NDB1V0	GCB0/IO34NDB1V0
F15	GND	GND	GND
F16	VCCENV	VCCENV	VCCENV
G1	EMC_DB[8]/IO40NDB5V0	EMC_DB[8]/GEC0/IO63NDB5V0	EMC_DB[8]/GEC0/IO80NDB5V0
G2	EMC_DB[7]/IO39PDB5V0	EMC_DB[7]/GEB1/IO62PDB5V0	EMC_DB[7]/GEB1/IO79PDB5V0
G3	EMC_DB[6]/IO39NDB5V0	EMC_DB[6]/GEB0/IO62NDB5V0	EMC_DB[6]/GEB0/IO79NDB5V0
G4	GFC2/IO41PDB5V0	GFC2/IO67PDB5V0	GFC2/IO84PDB5V0
G5	IO41NDB5V0	IO67NDB5V0	IO84NDB5V0
G6	GND	GND	GND
G7	VCC	VCC	VCC
G8	GND	GND	GND
G9	VCC	VCC	VCC
G10	GND	GND	GND
G11	VCCFPGAIOB1	VCCFPGAIOB1	VCCFPGAIOB1
G12	VPP	VPP	VPP
G13	TRSTB	TRSTB	TRSTB
G14	TMS	TMS	TMS
G15	TCK	TCK	TCK
G16	GNDENV	GNDENV	GNDENV
H1	GND	GND	GND
H2	EMC_DB[5]/IO38PPB5V0	EMC_DB[5]/GEA1/IO61PPB5V0	EMC_DB[5]/GEA1/IO78PPB5V0
H3	VCCFPGAIOB5	VCCFPGAIOB5	VCCFPGAIOB5
H4	EMC_DB[1]/IO36PDB5V0	EMC_DB[1]/GEB2/IO59PDB5V0	EMC_DB[1]/GEB2/IO76PDB5V0
H5	EMC_DB[0]/IO36NDB5V0	EMC_DB[0]/GEA2/IO59NDB5V0	EMC_DB[0]/GEA2/IO76NDB5V0
H6	VCCFPGAIOB5	VCCFPGAIOB5	VCCFPGAIOB5
H7	GND	GND	GND
H8	VCC	VCC	VCC
H9	GND	GND	GND
H10	VCC	VCC	VCC
H11	GND	GND	GND
H12	VJTAG	VJTAG	VJTAG

Notes:

1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.

FG484



Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/soc/products/solutions/package/docs.aspx>.

Pin Number	FG484	
	A2F200 Function	A2F500 Function
M21	VPP	VPP
M22	IO32NDB1V0	IO41NDB1V0
N1	GND	GND
N2	NC	IO70PDB5V0
N3	NC	IO70NDB5V0
N4	VCCRCOSC	VCCRCOSC
N5	VCCFPGAIOB5	VCCFPGAIOB5
N6	NC	IO68NDB5V0
N7	VCCFPGAIOB5	VCCFPGAIOB5
N8	GND	GND
N9	VCC	VCC
N10	GND	GND
N11	VCC	VCC
N12	GND	GND
N13	VCC	VCC
N14	GND	GND
N15	VCC	VCC
N16	NC	GND
N17	NC	NC
N18	VCCFPGAIOB1	VCCFPGAIOB1
N19	VCCENVM	VCCENVM
N20	GNDENVM	GNDENVM
N21	NC	NC
N22	GND	GND
P1	NC	IO69NDB5V0
P2	NC	IO69PDB5V0
P3	GNDRCOS	GNDRCOS
P4	GND	GND
P5	NC	NC
P6	NC	NC
P7	GND	GND
P8	VCC	VCC
P9	GND	GND
P10	VCC	VCC

Notes:

1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.

Pin Number	FG484	
	A2F200 Function	A2F500 Function
T1	GND	GND
T2	VCCMSSIOB4	VCCMSSIOB4
T3	GPIO_8/IO39RSB4V0	GPIO_8/IO48RSB4V0
T4	GPIO_11/IO57RSB4V0	GPIO_11/IO66RSB4V0
T5	GND	GND
T6	MAC_CLK	MAC_CLK
T7	VCCMSSIOB4	VCCMSSIOB4
T8	VCC33SDD0	VCC33SDD0
T9	VCC15A	VCC15A
T10	GND	GND
T11	GND33ADC0	GND33ADC0
T12	ADC7	ADC7
T13	NC	TM4
T14	NC	VAREF2
T15	VAREFOUT	VAREFOUT
T16	VCCMSSIOB2	VCCMSSIOB2
T17	SPI_1_DO/GPIO_24	SPI_1_DO/GPIO_24
T18	GND	GND
T19	NC	NC
T20	NC	NC
T21	VCCMSSIOB2	VCCMSSIOB2
T22	GND	GND
U1	GND	GND
U2	GPIO_5/IO42RSB4V0	GPIO_5/IO51RSB4V0
U3	GPIO_10/IO58RSB4V0	GPIO_10/IO67RSB4V0
U4	VCCMSSIOB4	VCCMSSIOB4
U5	MAC_RXD[1]/IO53RSB4V0	MAC_RXD[1]/IO62RSB4V0
U6	NC	NC
U7	VCC33AP	VCC33AP
U8	VCC33N	VCC33N
U9	CM1	CM1
U10	VAREF0	VAREF0
U11	GND33ADC1	GND33ADC1
U12	ADC4	ADC4

Notes:

1. Shading denotes pins that do not have completely identical functions from density to density. For example, the bank assignment can be different for an I/O, or the function might be available only on a larger density device.
2. *: Indicates that the signal assigned to the pins as a CLKBUF/CLKBUF_LVPECL/CLKBUF_LVDS goes through a glitchless mux. In order for the glitchless mux to operate correctly, the signal must be a free-running clock signal. Refer to the 'Glitchless MUX' section in the [SmartFusion Microcontroller Subsystem User's Guide](#) for more details.